

**Search Notes**

Application/Control No.

09/447,052

Examiner

Chau Nguyen

Applicant(s)/Patent under  
Reexamination

SUEHIRA, SEISHI

Art Unit

2176

**SEARCHED**

Class	Subclass	Date	Examiner
715	513	3/29/2006	CN
715	522	3/29/2006	CN
715	523	3/29/2006	CN
715	513	9/27/2006	CN
715	522-523	09/27/2006	CN
715	515	9/28/2006	CN
707	200	9/28/2006	CN
707	203	9/28/2006	CN
707	204	9/28/2006	CN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
715	513	5/11/2007	CN
715	522	5/11/2007	CN
715	523	5/11/2007	CN
707/200,203-204, PGPUB for Interference Search -see printout		5/12/2007	CN

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated Search on East Reports	3/29/2006	CN
NPL Search on IEEE Database	3/30/2006	CN
Updated Search on East Reports	9/27/2006	CN
	9/28/2006	CN
Updated Search on East Reports	5/11/2007	CN
	5/12/2007	CN
Discussed with Primary William Bashore	5/11/2007	CN